Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/014,095	OHNISHI, OSAMU	
Examiner	Art Unit	
Betsy L. Deppe	2611	

	SEARCHED				
Class	Subclass	Date	Examiner		
375	142	3/23/2006	BD		
375	144	3/23/2006	BD		
375	148	3/23/2006	BD		
375	150	3/23/2006	BD		
375	343	3/23/2006	BD		
370	335	3/23/2006	BD		
370	342	3/23/2006	BD		
370	441	3/23/2006	BD		
455	422.1	3/23/2006	BD		
455	436, 501	3/23/2006	BD		
455	456.6	3/23/2006	BD		
455	517	3/23/2006	BD		
455	524, 525	3/23/2006	BD		
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
1					

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Inventor name search	3/23/2006	BD
Text search (USPAT; US-PGPUB)	3/23/2006	BD
Text search (USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB)	3/28/2006	BD
text search (USPAT; US-PGPUB)	3/30/2006	BD
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